

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination SHINGAI ET AL.	
		Examiner Martin J. Angebrannndt	Art Unit 1756	Page 1 of 1

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*	B	US-2004/0191689	09-2004	Shingai et al.	430/270.13
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.